

Calibrat	ion or Measuren	nent Service	Measur	and Level or F	Range		nditions/Independent riable		E	xpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Luminous intensity	Tungsten lamp	Network of lamps and photometers, photometric bench	0.001	1	cd	Distribution temperature	2000 K to 3200 K	1.5 to 0.4, varies with measurand	%	2	95%	Yes	
Luminous intensity	Tungsten lamp	Network of lamps and photometers, photometric bench	1	1000	cd	Distribution temperature	2000 K to 3200 K	0.4	%	2	95%	Yes	
Luminous intensity	Tungsten lamp	Network of lamps and photometers, photometric bench	1000	100000	cd	Distribution temperature	2000 K to 3200 K	0.4 to 1.5, varies with measurand	%	2	95%	Yes	
Illuminance responsivity, tungsten source	Illuminance meter	Network of lamps and photometers, photometric bench			A/lx	Illuminance	0.001 lx to 0.1 lx	1.0 to 0.4, varies with illuminance	%	2	95%	Yes	
						Photocurrent	1E-11 A to 1E-06 A						
						Colour temperature	illuminant A						
Illuminance responsivity, tungsten source	Illuminance meter	Network of lamps and photometers, photometric bench			A/lx	Illuminance	0.1 lx to 1000 lx	0.4	%	2	95%	Yes	
						Photocurrent	1E-11 A to 1E-06 A						
						Colour temperature	illuminant A						
Illuminance responsivity, tungsten source	Illuminance meter	Network of lamps and photometers, photometric bench			A/lx	Illuminance	1000 lx to 10000 lx	0.4 to 1.5, varies with illuminance	%	2	95%	Yes	
						Photocurrent	1E-11 A to 1E-06 A						
						Colour temperature	illuminant A						
Luminous flux	Tungsten lamp	Goniophotometer	0.001	1	lm	Distribution temperature	2000 K to 3200 K	1.5	%	2	95%	Yes	



Calibrat	ion or Measuren	nent Service	Measur	and Level or F	Range		nditions/Independent riable		Ex	rpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Luminous flux	Tungsten lamp	Goniophotometer	1	100	lm	Distribution temperature	2000 K to 3200 K	1.5 to 0.6, varies with measurand	%	2	95%	Yes	
Luminous flux	Tungsten lamp	Goniophotometer	100	10000	lm	Distribution temperature	2000 K to 3200 K	0.6	%	2	95%	Yes	
Luminous flux	Tungsten lamp	Goniophotometer	10000	100000	lm	Distribution temperature	2000 K to 3200 K	0.6 to 1.5, varies with measurand	%	2	95%	Yes	
Illuminance	Tungsten lamp	Network of lamps and photometers, photometric bench	0.001	1	lx	Correlated colour temperature	2000 K to 3200 K	1.5 to 0.4, varies with measurand	%	2	95%	Yes	
Illuminance	Tungsten lamp	Network of lamps and photometers, photometric bench	1	1000	lx	Correlated colour temperature	2000 K to 3200 K	0.4	%	2	95%	Yes	
Illuminance	Tungsten lamp	Network of lamps and photometers, photometric bench	1000	1E+05	lx	Correlated colour temperature	2000 K to 3200 K	0.4 to 2.5, varies with measurand	%	2	95%	Yes	
Luminance	Tungsten-based source	Network of lamps and photometers, photometric bench	1	100	cd/m ²	Correlated colour temperature	2000 K to 3200 K	2.0 to 0.5, varies with measurand	%	2	95%	Yes	Area 50 mm ² to 2500 mm ²
Luminance	Tungsten-based source	Network of lamps and photometers, photometric bench	100	2000	cd/m ²	Correlated colour temperature	2000 K to 3200 K	0.5	%	2	95%	Yes	Area 50 mm ² to 2500 mm ²
Luminance	Tungsten-based source	Network of lamps and photometers, photometric bench	2000	2E+04	cd/m ²	Correlated colour temperature	2000 K to 3200 K	0.5 to 1.5, varies with measurand	%	2	95%	Yes	Area 50 mm ² to 2500 mm ²
Luminance responsivity	Luminance meter	Reference lamp / diffuser combination			A/(cd/m ²)	Luminance	10 cd/m ² to 100 cd/m ²	1.5	%	2	95%	Yes	Other types of sources can also be
						Type of source	tungsten lamp / diffuser combination						callibrated



Calibrati	ion or Measuren	nent Service	Measur	and Level or I	Range		nditions/Independent riable		E	κpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Luminance responsivity	Luminance meter	Reference lamp / diffuser combination			A/(cd/m ²)	Luminance	100 cd/m² to 1E+04 cd/m²	0.8	%	2	95%	Yes	Other types of sources
						Type of source	tungsten lamp / diffuser combination						can also be calibrated
Responsivity, spectral, power	Broadband detector	Cryogenic radiometers and synchrotron, and laser radiation and monochromators			A/W	Wavelength	200 nm to 400 nm	1.0	%	2	95%	Yes	
						Radiant power	< 4 µW						
						Bandwidth	2.5 nm						
Responsivity, spectral, power	Broadband detector	Double grating monochromator			A/W	Wavelength	400 nm to 800 nm	0.3	%	2	95%	Yes	
						Bandwidth	5 nm to 20 nm						
						Power level	0.1 μW to 10 μW						
Responsivity, spectral, power	Broadband detector	Double grating monochromator			A/W	Wavelength	800 nm to 1000 nm	0.9	%	2	95%	Yes	
						Bandwidth	5 nm to 20 nm						
						Power level	0.1 μW to 10 μW						
Responsivity, spectral, power	Broadband detector	Double grating monochromator			A/W	Wavelength	1000 nm to 1600 nm	1.5	%	2	95%	Yes	
						Bandwidth	5 nm to 20 nm						
						Power level	0.1 μW to 10 μW						
Responsivity, laser, power	General detector	Comparison with primary standard			A/W, V/W, reading/W	Wavelength	10.6 µm	0.3 to 1.0, varies with power level	%	2	95%	Yes	
						Power level	0.1 W to 1500 W		1				



Calibrat	ion or Measuren	nent Service	Measur	and Level or I	Range		nditions/Independent Iriable		E	κpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Responsivity, laser, power	General detector	Comparison with primary standard			A/W, V/W, reading/W		laser lines between 308 nm and 1064 nm	0.2 to 1.0, varies with power level	%	2	95%	Yes	
					1/04/	Power level	1 μW to 120 W						
Responsivity, laser, power	General detector	Comparison with primary standard			V/W or Reading/ W	Wavelengths	2106 nm and 2936 nm	1	%	2	95%	Yes	
						Power level	0.01 W to 10 W						
Responsivity, laser, power	General detector	Comparison with primary standard	0.01	10	w	Wavelength	351 nm	1.0	%	2	95%	Yes	Excimer laser lines, average power Approved on 07 May 2007
Responsivity, laser, power	General detector	Comparison with primary standard	0.01	20	w	Wavelength	308 nm	1.0	%	2	95%	Yes	Excimer laser lines, average power Approved on 07 May 2007
Responsivity, laser, power	General detector	Comparison with primary standard	0.01	30	w	Wavelength	248 nm	1.0	%	2	95%	Yes	Excimer laser lines, average power Approved on 07 May 2007



Calibrat	ion or Measuren	nent Service	Measur	and Level or I	Range		nditions/Independent ariable		E	kpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Responsivity, laser, power	General detector	Comparison with primary standard	0.01	3	w	Wavelength	193 nm	1.0	%	2	95%	Yes	Excimer laser lines, average power Approved on 07 May 2007
Responsivity, laser, power	General detector	Comparison with primary standard	0.01	3	w	Wavelength	157 nm	2.0	%	2	95%	Yes	Excimer laser lines, average power Approved on 07 May 2007
Irradiance, spectral	Tungsten lamp	Spectroradiometer	1E-04	0.25	(W/m ²)/nm		250 nm to 270 nm	12 to 5, varies with wavelength	%	2	95%	Yes	
						Bandwidth	0.5 nm to 20 nm						
Irradiance, spectral	Tungsten lamp	Spectroradiometer	1E-04	0.25	(W/m ²)/nm	Wavelength	270 nm to 400 nm	5 to 1.6, varies with wavelength	%	2	95%	Yes	
						Bandwidth	0.5 nm to 20 nm						
Irradiance, spectral	Tungsten lamp	Spectroradiometer	1E-04	0.25	(W/m²)/nm		400 nm to 800 nm	1.6	%	2	95%	Yes	
						Bandwidth	0.5 nm to 20 nm						
Irradiance, spectral	Tungsten lamp	Spectroradiometer	1E-04	0.25	(W/m ²)/nm		800 nm to 2000 nm	1.6 to 3, varies with wavelength	%	2	95%	Yes	
						Bandwidth	0.5 nm to 20 nm						
Irradiance, spectral	Tungsten lamp	Spectroradiometer	1E-04	0.25	(W/m ²)/nm	Wavelength	2000 nm to 2500 nm	3 to 5, varies with wavelength	%	2	95%	Yes	
						Bandwidth	0.5 nm to 20 nm						



Calibrati	on or Measuren	nent Service	Measura	and Level or F	Range		ditions/Independent riable		E)	cpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Irradiance, spectral	Deuterium lamp	Spectroradiometer	1E-05	0.02	(W/m ²)/nm		200 nm to 300 nm	10 to 4, varies with wavelength	%	2	95%	Yes	
						Bandwidth	4 nm						
Irradiance, spectral	Deuterium lamp	Spectroradiometer	1E-05	0.02	(W/m ²)/nm		300 nm to 400 nm	4 to 8, varies with wavelength	%	2	95%	Yes	
						Bandwidth	4 nm						
Radiance, spectral	Tungsten lamp	Spectroradiometer	5E-03	3E+02	W/(m² sr nm)	Wavelength range	250 nm to 650 nm	13.0 to 2.0, varies with wavelength	%	2	95%	Yes	
						Bandwidth	< 2 nm						
Radiance, spectral	Tungsten lamp	Spectroradiometer	5E-03	3E+02	W/(m² sr nm)	Wavelength range	< 2 1111	2.0 to 6.0, varies with wavelength	%	2	95%	Yes	
			-			Bandwidth	< 2 nm						
Radiance, spectral	Deuterium lamp	Spectroradiometer	1	1E+03	W/(m ² sr nm)	Wavelength range		4	%	2	95%	Yes	
						Bandwidth	0.2 nm						
Radiant intensity, spectral	Deuterium lamp	Spectroradiometer	1E-06	1E-03	W/(sr nm)	Wavelength range	200 nm to 350 nm	4	%	2	95%	Yes	
						Bandwidth	0.2 nm						
Transmittance, regular, spectral	Spectrally- neutral material	Direct/ cascading	1E-06	1		Wavelength	380 nm to 1000 nm	0.3(1 - logt), t transmittance	%	2	95%	Yes	
						Bandwidth	0.1 nm to 16 nm						
Reflectance, diffuse, spectral	Spectrally- neutral material	Absolute sphere reflectometer	0.1	1		Wavelength	360 nm to 830 nm	0.2	%	2	95%	Yes	
						Bandwidth	3 nm						
						Geometry	d/0, d/8						



Calibrat	ion or Measuren	nent Service	Measur	and Level or F	Range		nditions/Independent riable		E	κpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Reflectance, diffuse, spectral	Spectrally- neutral material	Absolute sphere reflectometer	0.1	1	1	Wavelength range	300 nm to 360 nm	0.5 to 0.2, varies with wavelength	%	2	95%	Yes	
						Bandwidth Specific measurement conditions	> 3 nm d/0 and d/8						
Reflectance, diffuse, spectral	Spectrally- neutral material	Absolute sphere reflectometer	0.1	1	1	Wavelength range		0.2 to 0.5, varies with wavelength	%	2	95%	Yes	
						Bandwidth Specific measurement conditions	> 3 nm d/0 and d/8						
Reflectance, regular, spectral	Spectrally- neutral material	Reference reflectometer	0.01	1		Wavelength range	220 nm to 20 µm	0.005 to 0.02, varies with wavelength and measurand		2	95%	No	Material with smooth surface
						Angle of incidence	7° to 80°						
						Spectral bandwidth	0.1 nm to 16 nm						
Reflectance, regular, spectral	Spectrally- neutral material	Gonioreflectometer	0.01	1		Wavelength range	10 nm to 30 nm	0.28 to 2, varies with value and wavelength	%	2	95%	Yes	Approved on 07 May 2007
BRDF	General materia	l Gonio-reflectometer	0.1	1		Wavelength range		1.0 to 0.4, varies with wavelength	%	2	95%	Yes	Spectrally- neutral material
						Bandwidth	> 3 nm						



Calibrat	ion or Measuren	nent Service	Measur	and Level or F	Range		nditions/Independent riable		Ex	κpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
						Angle of incidence / reflectance	0° to 85°						
BRDF	General materia	I Gonio-reflectometer	0.1	1		Wavelength range	400 nm to 850 nm	0.4	%	2	95%	Yes	Spectrally- neutral material
						Bandwidth	> 3 nm						
						Angle of incidence / reflectance	0° to 85°						
BRDF	General materia	I Gonio-reflectometer	0.1	1		Wavelength range		0.4 to 1.4, varies with wavelength	%	2	95%	Yes	Spectrally- neutral material
						Bandwidth	> 3 nm						
						Angle of incidence / reflectance	0° to 85°						
BRDF	General materia	I Gonio-reflectometer	0.03	infinite	1/sr	Wavelength range	250 nm to 900 nm	3.5 to 0.4, varies with wavelength	%	2	95%	Yes	Approved on 07 May 2007
						Bandwidth	3 nm						
						Geometry	arbiratry						
BRDF	General materia	I Gonio-reflectometer	0.03	infinite	1/sr	Wavelength range		0.4 to 0.5, varies with wavelength	%	2	95%	Yes	Approved on 07 May 2007
						Bandwidth	6 mm						
						Geometry	arbitrary						
Reflectance factor	Spectrally- neutral material	DMC 25 / Lambda900 - spectrometer	0.001	1		Wavelength range	300 nm to 2000 nm	1	%	2	95%	Yes	
						Bandwidth	5 nm to 10 nm						



Calibrati	ion or Measuren	nent Service	Measura	and Level or F	Range		iditions/Independent riable		Ex	rpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Radiance factor	General materia	I Gonio-reflectometer	0.1	1		Wavelength range	300 nm to 400 nm	1.0 to 0.4, varies with wavelength	%	2	95%	Yes	Spectrally- neutral material
						Bandwidth	> 3 nm	g					
						Geometry	0/45 and 45/0						
Radiance factor	General materia	l Gonio-reflectometer	0.1	1		Wavelength range		0.4	%	2	95%	Yes	Spectrally- neutral material
						Bandwidth	> 3 nm						
						Geometry	0/45 and 45/0						
Radiance factor	General materia	I Gonio-reflectometer	0.1	1		Wavelength range	850 nm to 1100 nm	0.4 to 1.4, varies with wavelength	%	2	95%	Yes	Spectrally- neutral material
						Bandwidth	> 3 nm						
						Geometry	0/45 and 45/0						
Radiance factor	General materia	I Gonio-reflectometer	0.01	infinite		Wavelength range	250 nm to 900 nm	3.5 to 0.4, varies with wavelength	%	2	95%	Yes	Approved on 07 May 2007
						Bandwidth	3 nm						
-			·			Geometry	0/45 and 45/0						
Radiance factor	General materia	I Gonio-reflectometer	0.01	infinite		Wavelength range		0.4 to 0.5, varies with wavelength	%	2	95%	Yes	Approved on 07 May 2007
						Bandwidth	6 nm						
						Geometry	0/45 and 45/0						
Radiance factor	Fluorescent material	Two-monochromator spectrometer	0.001	3.0		Wavelength range	300 nm to 800 nm	3	%	2	95%	Yes	
						Bandwidth	5 nm to 10 nm						



Calibrat	ion or Measuren	nent Service	Measur	and Level or F	Range		nditions/Independent riable		Ex	κpanded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Wavelength	Spectrally- selective transmitting material. Position of transmittance minimum	Reference spectrometer	240	653	nm	Wavelength	240 nm to 653 nm	0.15 to 0.3, varies with bandwidth	nm	2	95%	No	Approved on 07 May 2007
						Bandwidth	0.1 nm to 3 nm						
Distribution temperature	Tungsten lamp	Spectral distribution	2000	2350	K			20 to 10, varies with measurand	K	2	95%	No	
Distribution temperature	Tungsten lamp	Spectral distribution	2350	3000	K			10	K	2	95%	No	
Distribution temperature	Tungsten lamp	Spectral distribution	3000	3200	K			20	K	2	95%	No	
Correlated colour temperature	Tungsten lamp	Spectral distribution	2000	2350	K			10 to 6, varies with measurand	K	2	95%	No	
Correlated colour temperature	Tungsten lamp	Spectral distribution	2350	3000	K			6	K	2	95%	No	
Correlated colour temperature	Tungsten lamp	Spectral distribution	3000	3200	К			10	K	2	95%	No	
Colour, emitted, x, y	General source	Standard lamps with spectroradiometer	0	0.9		Bandwidth	broad band (> 100 nm)	0.001 to 0.0005, varies with measurand	%	2	95%	No	
Colour, emitted, x, y	General source	Standard lamps with spectroradiometer	0	0.9		Bandwidth	narrow band (< 100 nm)	0.005 to 0.0005, varies with measurand		2	95%	No	



Calibrat	ion or Measuren	nent Service	Measura	and Level or I	Range		ditions/Independent iable		E	panded Un	certainty		
Quantity	Instrument or Artifact	Instrument Type or Method	Minimum value	Maximum value	Units	Parameter	Specifications	Value	Units	Coverage factor	Level of Confidence	Is the expanded uncertainty a relative one?	Comments
Responsivity	Fibre optic power meter	Comparison with standard detector			A/W or Reading/ W	Wavelengths	650 nm, 850 nm, 1300 nm, 1550 nm	0.3 to 0.6, varies with power	%	2	95%	Yes	
						Power	1 nW to 3 mW						
Wavelength	Fibre optic source	Wavemeter	400	1100	nm	Power level	> 0.5 mW	1	pm	2	95%	No	
						Laser bandwidth	< 1 nm						
Wavelength	Fibre optic source	Wavemeter	1100	1600	nm	Power level	> 0.5 mW	3	pm	2	95%	No	
				-		Laser bandwidth	< 1 nm				-		